From models to mechanisms: defects and charge trapping in amorphous silicon nitride

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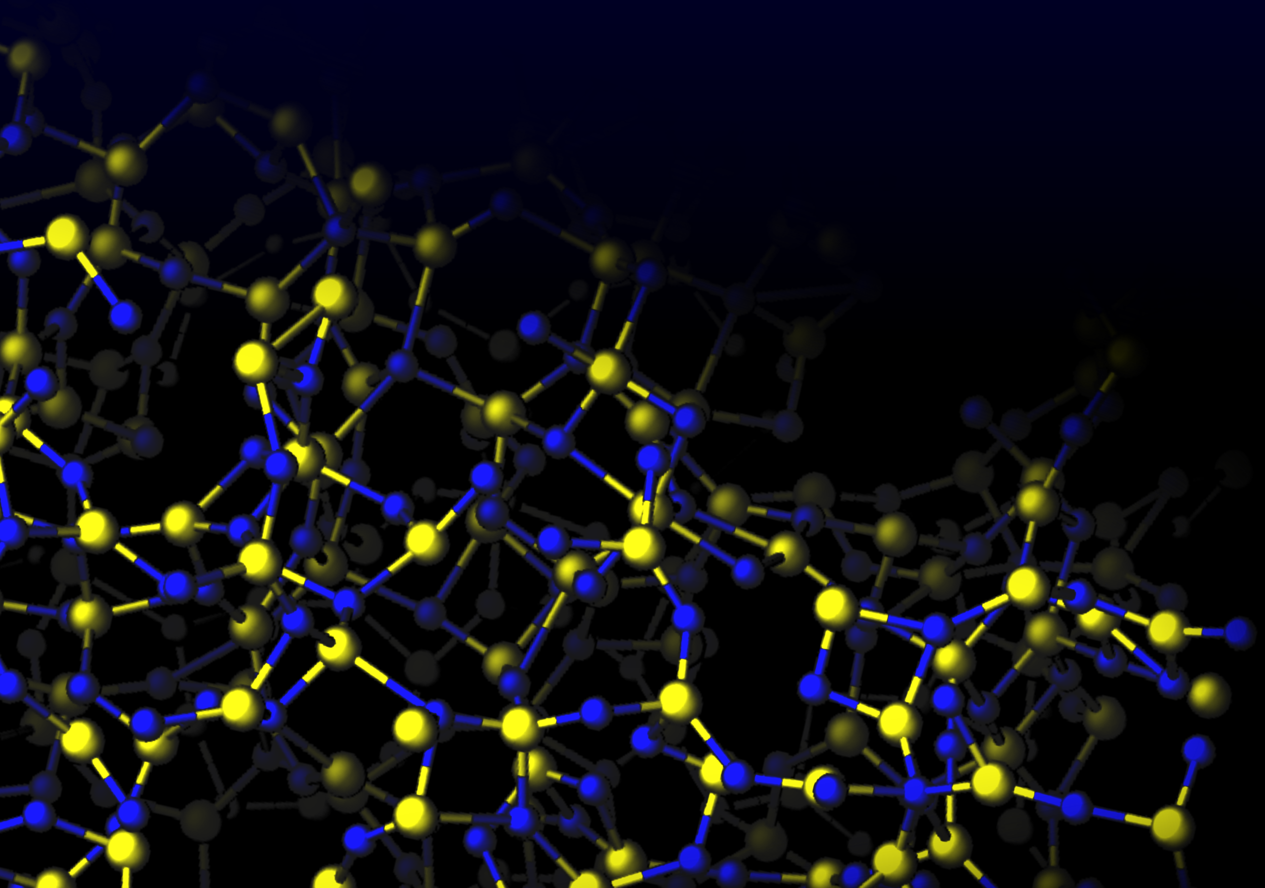
Citation

Hückmann, L. (2026, July 2). *From models to mechanisms: defects and charge trapping in amorphous silicon nitride*. Retrieved from https://hdl.handle.net/1887/4307230



Defects and Charge Trapping in Amorphous Silicon Nitride

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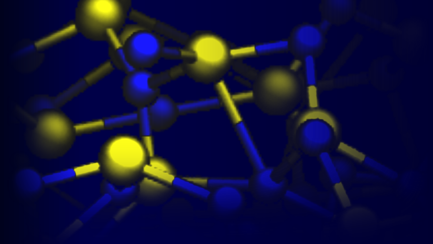
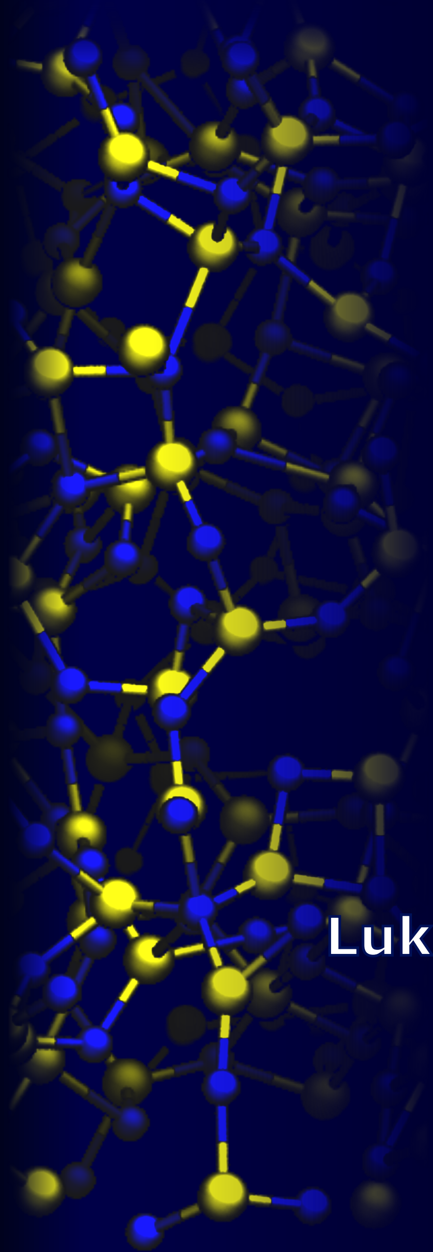


From Models to Mechanisms: Defects and Charge Trapping in Amorphous Silicon Nitride



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